



# Final Product/Process Change Notification

Document #: FPCN21520ZF

Issue Date: 10 Feb 2023

<b>Title of Change:</b>	Transfer of ONC25 technology to onsemi Aizu, Japan from current site onsemi Gresham, United States.	
<b>Proposed Changed Material First Ship Date:</b>	15 Aug 2023 or earlier if approved by customer	
<b>Current Material Last Order Date:</b>	N/A <i>Orders received after the Current Material Last Order Date expiration are to be considered as orders for new changed material as described in this PCN. Orders for current (unchanged) material after this date will be per mutual agreement and current material inventory availability.</i>	
<b>Current Material Last Delivery Date:</b>	N/A <i>The Current Material Last Delivery Date may be subject to change based on build and depletion of the current (unchanged) material inventory</i>	
<b>Product Category:</b>	Active components – Integrated circuits	
<b>Contact information:</b>	Contact your local onsemi Sales Office or <a href="mailto:Jaroslav.Supina@onsemi.com">Jaroslav.Supina@onsemi.com</a>	
<b>PCN Samples Contact:</b>	Contact your local onsemi Sales Office to place sample order. Sample requests are to be submitted no later than 45 days after publication of this change notification. Samples delivery timing will be subject to request date, sample quantity and special customer packing/label requirements.	
<b>Sample Availability Date:</b>	15 Mar 2023	
<b>PPAP Availability Date:</b>	10 Feb 2023	
<b>Additional Reliability Data:</b>	Contact your local onsemi Sales Office or <a href="mailto:Vladislav.Hrachovec@onsemi.com">Vladislav.Hrachovec@onsemi.com</a>	
<b>Type of Notification:</b>	This is a Final Product/Process Change Notification (FPCN) sent to customers. The change will be implemented at 'Proposed Change Material First Ship Date' in compliance to J-STD-46 or ZVEI, or earlier upon customer approval, or per our signed agreements. onsemi will consider this proposed change and it's conditions acceptable, unless an inquiry is made in writing within 45 days of delivery of this notice. To do so, contact <a href="mailto:PCN.Support@onsemi.com">PCN.Support@onsemi.com</a> .	
<b>Change Category</b>		
<b>Category</b>	<b>Type of Change</b>	
Process - Wafer Production	Move of all or part of wafer fab to a different location/site/subcontractor	
<b>Description and Purpose:</b>		
<p>The onsemi Aizu, Wafer Fab located at Aizuwakamatsu, Japan has been qualified to process the ONC25 CMOS process.</p> <p>Tool sets are different but the exact same masking layers and steps are being used in the Aizu Fab.</p> <p>This change is implemented to mitigate potential supply disruption; customers are encouraged to urgently review this change in order to minimize any potential impact to their supply chain.</p>		
	<b>From</b>	<b>To</b>
<b>Fab Locations</b>	onsemi, Gresham	onsemi, Aizu
There is no product marking change as a result of this change.		

<b>Reason / Motivation for Change:</b>	Source/Supply/Capacity Changes Process/Materials Change
<b>Anticipated impact on fit, form, function, reliability, product safety or manufacturability:</b>	The device has been qualified and validated based on the same Product Specification. The device has successfully passed the qualification tests. Potential impacts can be identified, but due to testing performed by onsemi in relation to the PCN, associated risks are verified and excluded.  No anticipated impacts.
<b>Sites Affected:</b>	
<b>onsemi Sites</b>	<b>External Foundry/Subcon Sites</b>
onsemi Aizu, Japan	None
<b>Marking of Parts/ Traceability of Change:</b>	Customs source information will be updated on product label, and product will be identified by encoded date code.

**Reliability Data Summary:**

**QV1 DEVICE NAME:** NCV8165ML330TBG

**RMS** : S82347

**PACKAGE** : DFNW8 AU SNGL HPBF WFS

Test	Specification	Condition	Interval	Results
HTOL	JESD22-A108	Ta=125°C, bias at 1.2X Nominal (not to exceed Max rated)	2016 hrs	0/240
ESD HBM	JESD22-A114	c = 0, Test @ R & H	2kV	0/3
ESD CDM	JESD22-A115	c = 0, Test @ R	1kV	0/3
LU	JESD78	Test @ EP; Test & Stress @ R & H	LU+>100mA LU->100mA	0/6
ED	ON Data Sheet	Cpk > 1.67 Test @ R, H, C	Cpk>1.67	pass

**Table 1: Reliability Evaluation Results – Die related and Characterization tests**

Test	Specification	Condition	Interval	Results
HTSL	JESD22-A103	Ta= 150°C	2016 hrs	0/240
PC	J-STD-020 JESD-A113	MSL 1 @ 260 °C	Results	0/all
PC-TC	JESD22-A104	Ta= -65°C to +150°C	1000 cyc	0/240
PC-UHAST	JESD22-A118	Ta = 130°C, RH=85%, PSIG = 18.8, unbiased	96 hrs	0/240
PC-HAST	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs	0/240
BS	AEC-Q100-001	per assembly spec	Results	0/120
BPS	M883 Method 2011	per assembly spec	Results	0/120

**Table 2: Reliability Evaluation Results – Package related data**

**QV2 DEVICE NAME:** NCP161AFCS180T2G

**RMS** : S34344

**PACKAGE** : FCDCA BUMP PB FREE

Test	Specification	Condition	Interval	Results
HTOL	JESD22-A108	Ta=125°C, bias at 1.2X Nominal (not to exceed Max rated)	1008 hrs	0/240
ESD HBM	AEC-Q100-002	c = 0, Test @ R & H	2kV	0/3
ESD CDM	AEC-Q100-011	c = 0, Test @ R	1kV	0/3
LU	JESD78	Test @ EP; Test & Stress @ R & H	LU+>100mA LU->100mA	0/6
ED	ON Data Sheet	Cpk > 1.67 Test @ R, H, C	Cpk>1.67	pass

**Table 3: Reliability Evaluation Results – Die related and Characterization tests**

Test	Specification	Condition	Interval	Results
HTSL	JESD22-A103	Ta= 150°C	1008 hrs	0/240
PC	J-STD-020 JESD-A113	MSL 1 @ 260 °C	Results	0/all
PC-TC	JESD22-A104	Ta= -65°C to +150°C	1000 cyc	0/240
PC-UHAST	JESD22-A118	Ta = 130°C, RH=85%, PSIG = 18.8, unbiased	96 hrs	0/240
PC-HAST	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs	0/240
BS	AEC-Q100-001	per assembly spec	Results	0/120
BPS	M883 Method 2011	per assembly spec	Results	0/120

Table 4: Reliability Evaluation Results – Package related data

QV2 DEVICE NAME: NCP161AFCT180T2G

RMS : S34346, S55661, S56442

PACKAGE : WLCSP4 SNGL HPBF, WLCSP-4

Test	Specification	Condition	Interval	Results
HTOL	JESD22-A108	Ta=125°C, bias at 1.2X Nominal (not to exceed Max rated)	2016 hrs	0/240
ELFR	JESD22-A108	Ta = 125°C, bias at 1.2X Nominal (not to exceed Max rated)	48h	0/2400
ESD HBM	AEC-Q100-002	c = 0, Test @ R & H	2kV	0/3
ESD CDM	AEC-Q100-011	c = 0, Test @ R	1kV	0/3
LU	JESD78	Test @ EP; Test & Stress @ R & H	LU+>100mA LU->100mA	0/6
ED	ON Data Sheet	Cpk > 1.67 Test @ R, H, C	Cpk>1.67	pass

Table 5: Reliability Evaluation Results – Die related and Characterization tests

Test	Specification	Condition	Interval	Results
HTSL	JESD22-A103	Ta= 150°C	1008 hrs	0/240
PC	J-STD-020 JESD-A113	MSL 1 @ 260 °C	Results	0/all
PC-TC	JESD22-A104	Ta= -65°C to +150°C	1000 cyc	0/240
PC-UHAST	JESD22-A118	Ta = 130°C, RH=85%, PSIG = 18.8, unbiased	96 hrs	0/240
PC-HAST	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs	0/240
BS	AEC-Q100-001	per assembly spec	Results	0/120
BPS	M883 Method 2011	per assembly spec	Results	0/120

Table 6: Reliability Evaluation Results – Package related data

QV2 DEVICE NAME: NCP161AMX180TBG

RMS : S34343,

PACKAGE : XDFN4 LDLSS 1\*1\*.4MM PBF

Test	Specification	Condition	Interval	Results
HTOL	JESD22-A108	Ta=125°C, bias at 1.2X Nominal (not to exceed Max rated)	1008 hrs	0/240
ESD HBM	JESD22-A114	c = 0, Test @ R & H	2kV	0/3
ESD CDM	JESD22-A115	c = 0, Test @ R	1kV	0/3
LU	JESD78	Test @ EP; Test & Stress @ R & H	LU+>100mA LU->100mA	0/6
ED	ON Data Sheet	Cpk > 1.67 Test @ R, H, C	Cpk>1.67	pass

Table 7: Reliability Evaluation Results – Die related and Characterization tests

Test	Specification	Condition	Interval	Results
HTSL	JESD22-A103	Ta= 150°C	1008 hrs	0/240
PC	J-STD-020 JESD-A113	MSL 1 @ 260 °C	Results	0/all
SAT (PC)	as outlined in 12MSB17722C	Compare for Delamination before and after PC	Results	0/66
PC-TC	JESD22-A104	Ta= -65°C to +150°C	1000 cyc	0/240
SAT (TC500)	as outlined in 12MSB17722C	Compare for Delamination before and after PC	Results	0/66
WBP (TC500)	as outlined in 12MSB17722C	Custom Destructive Physical Analysis - Wire Pull	Results	passed
BS (TC500)	as outlined in 12MSB17722C	Custom Destructive Physical Analysis - Bond Shear	Results	passed
DPA (TC500)	as outlined in 12MSB17722C	Custom Destructive Physical Analysis Following PC + TC	Results	passed
PC-UHAST	JESD22-A118	Ta = 130°C, RH=85%, PSIG = 18.8, unbiased	96 hrs	0/240
PC-HAST	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs	0/240
BS	AEC-Q100-001	per assembly spec	Results	0/120
BPS	M883 Method 2011	per assembly spec	Results	0/120

Table 8: Reliability Evaluation Results – Package related data

QV2 DEVICE NAME: NCP170AXV300T2G

RMS : S33743

PACKAGE : SOT-563-6 AU SNGL HPBF

Test	Specification	Condition	Interval	Results
HTOL	JESD22-A108	Ta=125°C, bias at 1.2X Nominal (not to exceed Max rated)	2016 hrs	0/240
ELFR	JESD22-A108	Ta=125°C, bias at 1.2X Nominal (not to exceed Max rated)	48h	0/2400
ESD HBM	JESD22-A114	c = 0, Test @ R & H	2kV	0/3
ESD CDM	JESD22-A115	c = 0, Test @ R	1kV	0/3
LU	JESD78	Test @ EP; Test & Stress @ R & H	LU->100mA LU->100mA	0/6
ED	ON Data Sheet	Cpk > 1.67 Test @ R, H, C	Cpk>1.67	pass

Table 9: Reliability Evaluation Results – Die related and Characterization tests

Test	Specification	Condition	Interval	Results
HTSL	JESD22-A103	Ta= 150°C	2016 hrs	0/240
PC	J-STD-020 JESD-A113	MSL 1 @ 260 °C	Results	0/all
PC-TC	JESD22-A104	Ta= -65°C to +150°C	2000 cyc	0/240
PC-UHAST	JESD22-A118	Ta = 130°C, RH=85%, PSIG = 18.8, unbiased	192 hrs	0/240
PC-HAST	JESD22-A110	130°C, 85% RH, 18.8psig, bias	528 hrs	0/240
BS	AEC-Q100-001	per assembly spec	Results	0/120
BPS	M883 Method 2011	per assembly spec	Results	0/120

Table 10: Reliability Evaluation Results – Package related data

**QV4 DEVICE NAME: NCV59748MLADJTBG**

**RMS : S46066,**

**PACKAGE : DFNW10 CU SNGL HPBF WFS**

Test	Specification	Condition	Interval	Results
HTOL	JESD22-A108	Ta=125°C, bias at 1.2X Nominal (not to exceed Max rated)	2016 hrs	0/80
ESD HBM	JESD22-A114	c = 0, Test @ R & H	2kV	0/3
ESD CDM	JESD22-A115	c = 0, Test @ R	1kV	0/3
LU	JESD78	Test @ EP; Test & Stress @ R & H	LU+>100mA LU->100mA	0/6
ED	ON Data Sheet	Cpk > 1.67 Test @ R, H, C	Cpk>1.67	pass

**Table 11: Reliability Evaluation Results – Die related and Characterization tests**

**QV4 DEVICE NAME: NCV59748MNADJTBG**

**RMS : S46068,**

**PACKAGE : DFN10 2AU SNGL HPBF**

Test	Specification	Condition	Interval	Results
HTOL	JESD22-A108	Ta=125°C, bias at 1.2X Nominal (not to exceed Max rated)	2016 hrs	0/80
ED	ON Data Sheet	Cpk > 1.67 Test @ R, H, C	Cpk>1.67	pass

**Table 12: Reliability Evaluation Results – Die related and Characterization tests**

**QV4 DEVICE NAME: NCV59749MNADJTBG**

**RMS : S46064,**

**PACKAGE : QFN20 5\*5 AU SNGL PBF**

Test	Specification	Condition	Interval	Results
HTOL	JESD22-A108	Ta=125°C, bias at 1.2X Nominal (not to exceed Max rated)	2016 hrs	0/80
ED	ON Data Sheet	Cpk > 1.67 Test @ R, H, C	Cpk>1.67	pass

**Table 13: Reliability Evaluation Results – Die related and Characterization tests**

**QV5 DEVICE NAME: NCV8164ASN280T1G**

**RMS : S54972, S54973, S66766**

**PACKAGE : TSOP 5 EPOXY MATRIX PBF**

Test	Specification	Condition	Interval	Results
HTOL	JESD22-A108	Ta=125°C, bias at 1.2X Nominal (not to exceed Max rated)	2016 hrs	0/240
ESD HBM	JESD22-A114	c = 0, Test @ R & H	2kV	0/3
ESD CDM	JESD22-A115	c = 0, Test @ R	1kV	0/3
LU	JESD78	Test @ EP; Test & Stress @ R & H	LU+>100mA LU->100mA	0/6
ED	ON Data Sheet	Cpk > 1.67 Test @ R, H, C	Cpk>1.67	pass

**Table 14: Reliability Evaluation Results – Die related and Characterization tests**

Test	Specification	Condition	Interval	Results
HTSL	JESD22-A103	Ta= 150°C	2016 hrs	0/240
PC	J-STD-020 JESD-A113	MSL 1 @ 260 °C	Results	0/all
PC-TC	JESD22-A104	Ta= -65°C to +150°C	1000 cyc	0/240
PC-UHAST	JESD22-A118	Ta = 130°C, RH=85%, PSIG = 18.8, unbiased	192 hrs	0/240



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<b>PC-HAST</b>	JESD22-A110	130°C, 85% RH, 18.8psig, bias	192 hrs	0/240
<b>BS</b>	AEC-Q100-001	per assembly spec	Results	0/120
<b>BPS</b>	M883 Method 2011	per assembly spec	Results	0/120

**Table 15: Reliability Evaluation Results – Package related data**

**QV6 DEVICE NAME:** NCV8187AMT330TAG  
**RMS** : S56004, S56005, S56006  
**PACKAGE** : WDFN6 AU SNGL HPBF

Test	Specification	Condition	Interval	Results
<b>HTOL</b>	JESD22-A108	Ta=125°C, bias at 1.2X Nominal (not to exceed Max rated)	2016 hrs	0/240
<b>ESD HBM</b>	JESD22-A114	c = 0, Test @ R & H	2kV	0/3
<b>ESD CDM</b>	JESD22-A115	c = 0, Test @ R	1kV	0/3
<b>LU</b>	JESD78	Test @ EP; Test & Stress @ R & H	LU+>100mA LU->100mA	0/6
<b>ED</b>	ON Data Sheet	Cpk > 1.67 Test @ R, H, C	Cpk>1.67	pass

**Table 16: Reliability Evaluation Results – Die related and Characterization tests**

### Electrical Characteristics Summary:

Electrical characteristics are not impacted. All Data Sheet specifications remain the same.

### List of Affected Parts:

**Note:** Only the standard (off the shelf) part numbers are listed in the parts list. Any custom parts affected by this PCN are shown in the customer specific PCN addendum in the PCN email notification, or on the [PCN Customized Portal](#).

Current Part Number	New Part Number	Qualification Vehicle
NCV8130BMX080TCG	N/A	NCV59748MLADJTBG,NCV59748MNADJTBG,NCV59749MNADJTBG
NCV8130BMX100TCG	N/A	NCV59748MLADJTBG,NCV59748MNADJTBG,NCV59749MNADJTBG
NCV8130BMX120TCG	N/A	NCV59748MLADJTBG,NCV59748MNADJTBG,NCV59749MNADJTBG
NCV8130BMX150TCG	N/A	NCV59748MLADJTBG,NCV59748MNADJTBG,NCV59749MNADJTBG
NCV8133BMX100TCG	N/A	NCV59748MLADJTBG,NCV59748MNADJTBG,NCV59749MNADJTBG
NCV8133BMX120TCG	N/A	NCV59748MLADJTBG,NCV59748MNADJTBG,NCV59749MNADJTBG
NCV8133BMX130TCG	N/A	NCV59748MLADJTBG,NCV59748MNADJTBG,NCV59749MNADJTBG
NCV8133BMX150TCG	N/A	NCV59748MLADJTBG,NCV59748MNADJTBG,NCV59749MNADJTBG
NCV8720BMT105TBG	N/A	NCV59748MLADJTBG,NCV59748MNADJTBG,NCV59749MNADJTBG
NCV8720BMT110TBG	N/A	NCV59748MLADJTBG,NCV59748MNADJTBG,NCV59749MNADJTBG
NCV8720BMT115TBG	N/A	NCV59748MLADJTBG,NCV59748MNADJTBG,NCV59749MNADJTBG
NCV8720BMT120TBG	N/A	NCV59748MLADJTBG,NCV59748MNADJTBG,NCV59749MNADJTBG
NCV8720BMT125TBG	N/A	NCV59748MLADJTBG,NCV59748MNADJTBG,NCV59749MNADJTBG



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NCV8720BMT180TBG	N/A	NCV59748MLADJTBG,NCV59748MNADJTBG,NCV59749MNADJTBG
NCV8720BMTW090TBG	N/A	NCV59748MLADJTBG,NCV59748MNADJTBG,NCV59749MNADJTBG
NCV8720BMTW110TBG	N/A	NCV59748MLADJTBG,NCV59748MNADJTBG,NCV59749MNADJTBG
NCV8720BMTW120TBG	N/A	NCV59748MLADJTBG,NCV59748MNADJTBG,NCV59749MNADJTBG
NCV8720BMTW130TBG	N/A	NCV59748MLADJTBG,NCV59748MNADJTBG,NCV59749MNADJTBG
NCV8720BMTW150TBG	N/A	NCV59748MLADJTBG,NCV59748MNADJTBG,NCV59749MNADJTBG
NCV8720BMTW180TBG	N/A	NCV59748MLADJTBG,NCV59748MNADJTBG,NCV59749MNADJTBG
SCV8720BMTW150TBG	N/A	NCV59748MLADJTBG,NCV59748MNADJTBG,NCV59749MNADJTBG
NCV8135AMT040TBG	N/A	NCV8187AMT330TAG
NCV8135AMT120TBG	N/A	NCV8187AMT330TAG
NCV8135AMTW040TBG	N/A	NCV8187AMT330TAG
NCV8135AMTW075TBG	N/A	NCV8187AMT330TAG
NCV8135AMTW120TBG	N/A	NCV8187AMT330TAG
NCV8135BMT040TBG	N/A	NCV8187AMT330TAG
NCV8135BMTW040TBG	N/A	NCV8187AMT330TAG
NCV8160AMX180TBG	N/A	NCP161AMX180TBG, NCP161AFCS180T2G, NCP161AFCT180T2G
NCV8160AMX250TBG	N/A	NCP161AMX180TBG, NCP161AFCS180T2G, NCP161AFCT180T2G
NCV8160AMX280TBG	N/A	NCP161AMX180TBG, NCP161AFCS180T2G, NCP161AFCT180T2G
NCV8160AMX290TBG	N/A	NCP161AMX180TBG, NCP161AFCS180T2G, NCP161AFCT180T2G
NCV8160AMX300TBG	N/A	NCP161AMX180TBG, NCP161AFCS180T2G, NCP161AFCT180T2G
NCV8160AMX330TBG	N/A	NCP161AMX180TBG, NCP161AFCS180T2G, NCP161AFCT180T2G
NCV8161AMX180TBG	N/A	NCP161AMX180TBG, NCP161AFCS180T2G, NCP161AFCT180T2G
NCV8161AMX250TBG	N/A	NCP161AMX180TBG, NCP161AFCS180T2G, NCP161AFCT180T2G
NCV8161AMX280TBG	N/A	NCP161AMX180TBG, NCP161AFCS180T2G, NCP161AFCT180T2G
NCV8161AMX290TBG	N/A	NCP161AMX180TBG, NCP161AFCS180T2G, NCP161AFCT180T2G
NCV8161AMX300TBG	N/A	NCP161AMX180TBG, NCP161AFCS180T2G, NCP161AFCT180T2G
NCV8161AMX330TBG	N/A	NCP161AMX180TBG, NCP161AFCS180T2G, NCP161AFCT180T2G
NCV8161ASN180T1G	N/A	NCV8164ASN280T1G
NCV8161ASN280T1G	N/A	NCV8164ASN280T1G
NCV8161ASN300T1G	N/A	NCV8164ASN280T1G
NCV8161ASN330T1G	N/A	NCV8164ASN280T1G
NCV8161BMX280TBG	N/A	NCP161AMX180TBG, NCP161AFCS180T2G, NCP161AFCT180T2G
NCV8161BSN280T1G	N/A	NCV8164ASN280T1G
NCV8161BSN300T1G	N/A	NCV8164ASN280T1G
NCV8161BSN330T1G	N/A	NCV8164ASN280T1G



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NCV8163AMX120TBG	N/A	NCV8165ML330TBG
NCV8163AMX150TBG	N/A	NCV8165ML330TBG
NCV8163AMX180TBG	N/A	NCV8165ML330TBG
NCV8163AMX270TBG	N/A	NCV8165ML330TBG
NCV8163AMX280TBG	N/A	NCV8165ML330TBG
NCV8163AMX300TBG	N/A	NCV8165ML330TBG
NCV8163AMX330TBG	N/A	NCV8165ML330TBG
NCV8163ASN120T1G	N/A	NCV8164ASN280T1G
NCV8163ASN180T1G	N/A	NCV8164ASN280T1G
NCV8163ASN270T1G	N/A	NCV8164ASN280T1G
NCV8163ASN280T1G	N/A	NCV8164ASN280T1G
NCV8163ASN300T1G	N/A	NCV8164ASN280T1G
NCV8163ASN330T1G	N/A	NCV8164ASN280T1G
SCV8163AMX280TBG	N/A	NCV8165ML330TBG
NCV8170AMX120TCG	N/A	NCP170AXV300T2G
NCV8170AMX150TCG	N/A	NCP170AXV300T2G
NCV8170AMX180TCG	N/A	NCP170AXV300T2G
NCV8170AMX250TCG	N/A	NCP170AXV300T2G
NCV8170AMX280TCG	N/A	NCP170AXV300T2G
NCV8170AMX300TCG	N/A	NCP170AXV300T2G
NCV8170AMX330TCG	N/A	NCP170AXV300T2G
NCV8170AMX360TCG	N/A	NCP170AXV300T2G
NCV8170AXV150T2G	N/A	NCP170AXV300T2G
NCV8170AXV180T2G	N/A	NCP170AXV300T2G
NCV8170AXV250T2G	N/A	NCP170AXV300T2G
NCV8170AXV280T2G	N/A	NCP170AXV300T2G
NCV8170AXV300T2G	N/A	NCP170AXV300T2G
NCV8170AXV330T2G	N/A	NCP170AXV300T2G
NCV8170AXV360T2G	N/A	NCP170AXV300T2G
NCV8170BMX120TCG	N/A	NCP170AXV300T2G
NCV8170BMX150TCG	N/A	NCP170AXV300T2G
NCV8170BMX180TCG	N/A	NCP170AXV300T2G
NCV8170BMX250TCG	N/A	NCP170AXV300T2G
NCV8170BMX280TCG	N/A	NCP170AXV300T2G
NCV8170BMX310TCG	N/A	NCP170AXV300T2G





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NCV8170BMX330TCG	N/A	NCP170AXV300T2G
NCV8170BMX360TCG	N/A	NCP170AXV300T2G
NCV8170BXV120T2G	N/A	NCP170AXV300T2G
NCV8170BXV150T2G	N/A	NCP170AXV300T2G
NCV8170BXV180T2G	N/A	NCP170AXV300T2G
NCV8170BXV250T2G	N/A	NCP170AXV300T2G
NCV8170BXV280T2G	N/A	NCP170AXV300T2G
NCV8170BXV300T2G	N/A	NCP170AXV300T2G
NCV8170BXV310T2G	N/A	NCP170AXV300T2G
NCV8170BXV330T2G	N/A	NCP170AXV300T2G
NCV8170BXV360T2G	N/A	NCP170AXV300T2G
NCV59749MNADJTBG	N/A	NCV59748MLADJTBG,NCV59748MNADJTBG,NCV59749MNADJTBG
NCV59748MWADJTBG	N/A	NCV59748MLADJTBG,NCV59748MNADJTBG,NCV59749MNADJTBG
NCV59748MNADJTBG	N/A	NCV59748MLADJTBG,NCV59748MNADJTBG,NCV59749MNADJTBG
NCV59748MLADJTBG	N/A	NCV59748MLADJTBG,NCV59748MNADJTBG,NCV59749MNADJTBG
NCV59744MNADJTBG	N/A	NCV59748MLADJTBG,NCV59748MNADJTBG,NCV59749MNADJTBG
NCV8186BMN330TAG	N/A	NCV59748MLADJTBG,NCV59748MNADJTBG,NCV59749MNADJTBG
NCV8186BMN175TAG	N/A	NCV59748MLADJTBG,NCV59748MNADJTBG,NCV59749MNADJTBG
NCV8186AMN330TAG	N/A	NCV59748MLADJTBG,NCV59748MNADJTBG,NCV59749MNADJTBG
NCV8163AMX250TBG	N/A	NCV8165ML330TBG
SCV8720BMTW180TBG	N/A	NCV59748MLADJTBG,NCV59748MNADJTBG,NCV59749MNADJTBG
SCV8720BMTW120TBG	N/A	NCV59748MLADJTBG,NCV59748MNADJTBG,NCV59749MNADJTBG
NCV8720BMT160TBG	N/A	NCV59748MLADJTBG,NCV59748MNADJTBG,NCV59749MNADJTBG
NCV8720BMT145TBG	N/A	NCV59748MLADJTBG,NCV59748MNADJTBG,NCV59749MNADJTBG
NCV8720BMT140TBG	N/A	NCV59748MLADJTBG,NCV59748MNADJTBG,NCV59749MNADJTBG
NCV8133BMX110TCG	N/A	NCV59748MLADJTBG,NCV59748MNADJTBG,NCV59749MNADJTBG
NCV8130BMX130TCG	N/A	NCV59748MLADJTBG,NCV59748MNADJTBG,NCV59749MNADJTBG
NCV8130BMX110TCG	N/A	NCV59748MLADJTBG,NCV59748MNADJTBG,NCV59749MNADJTBG